

**Search Notes**

Application/Control No.

10/821,167

Examiner

B. Clayton McCraw

Applicant(s)/Patent under  
Reexamination

JEONG ET AL.

Art Unit

3744

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with Primary Examiner, William Tapolcai	4/24/2006	BCM
Consulted with Primary Examiner, William Doerrler	4/27/2006	BCM
Conducted Inventor Name Search	4/27/2006	BCM
EAST Search Notes Attached	4/27/2006	BCM